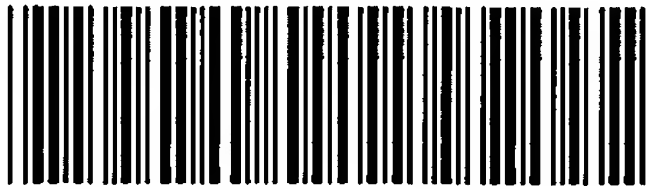


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/649,172	SAIKA, NOBUYUKI	
	Examiner	Art Unit	
	Marc R. Filipczyk	2163	

SEARCHED			
Class	Subclass	Date	Examiner
707	1-10, 100, 200-206	9/28/2006	MF
709	203, 213	9/28/2006	MF
710	1,5,38	9/28/2006	MF

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
707	1, 10	9/28/2006	MF
707	200	9/28/2006	MF

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST; IEEE; CiteSeer; file server, compar/match file/ids, mirror/replicate target/source, consult Coby (AU2161)	9/28/2006	MF
update search using previous concept	9/28/2006	MF